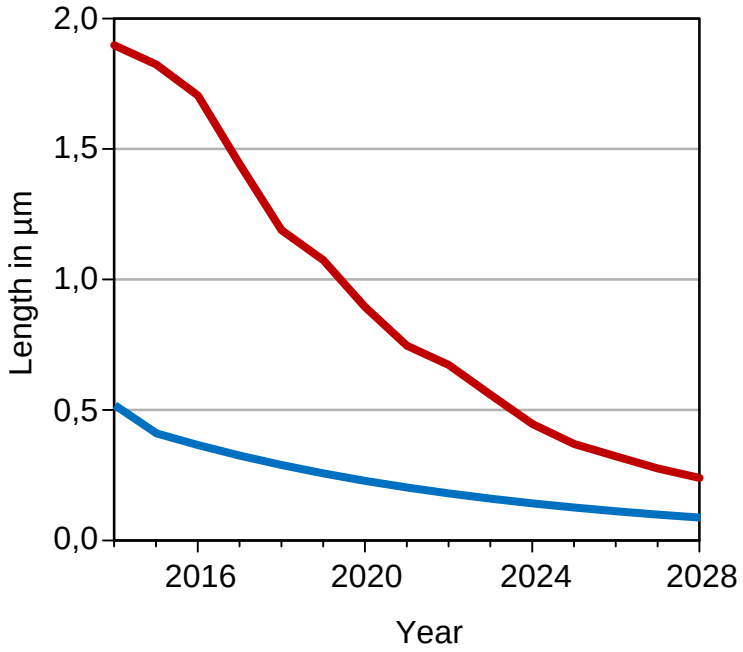
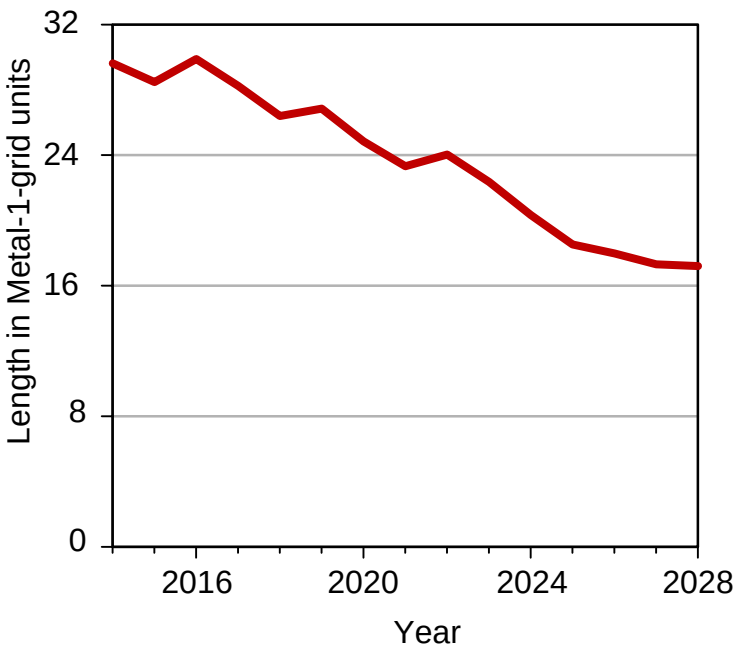
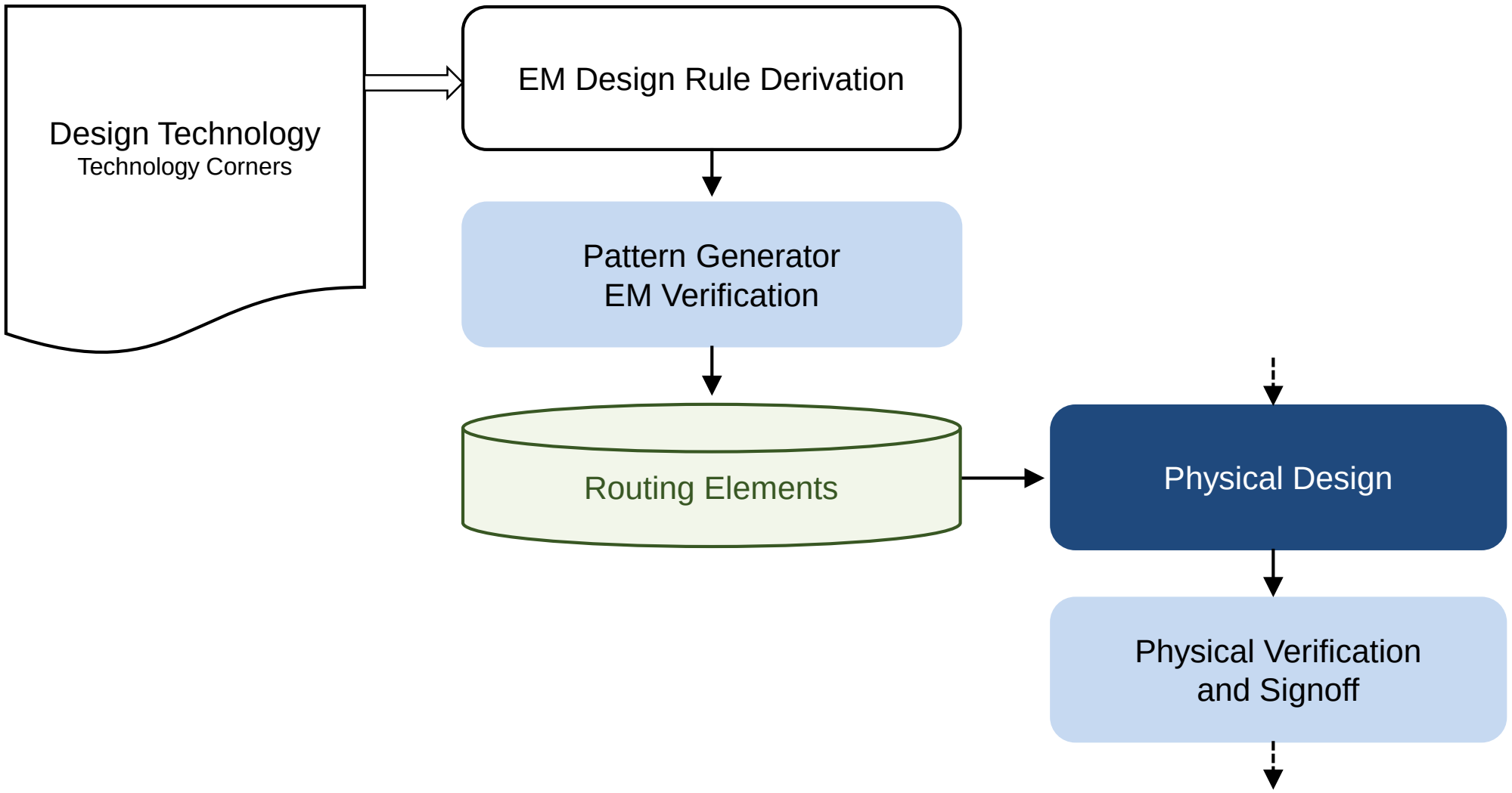
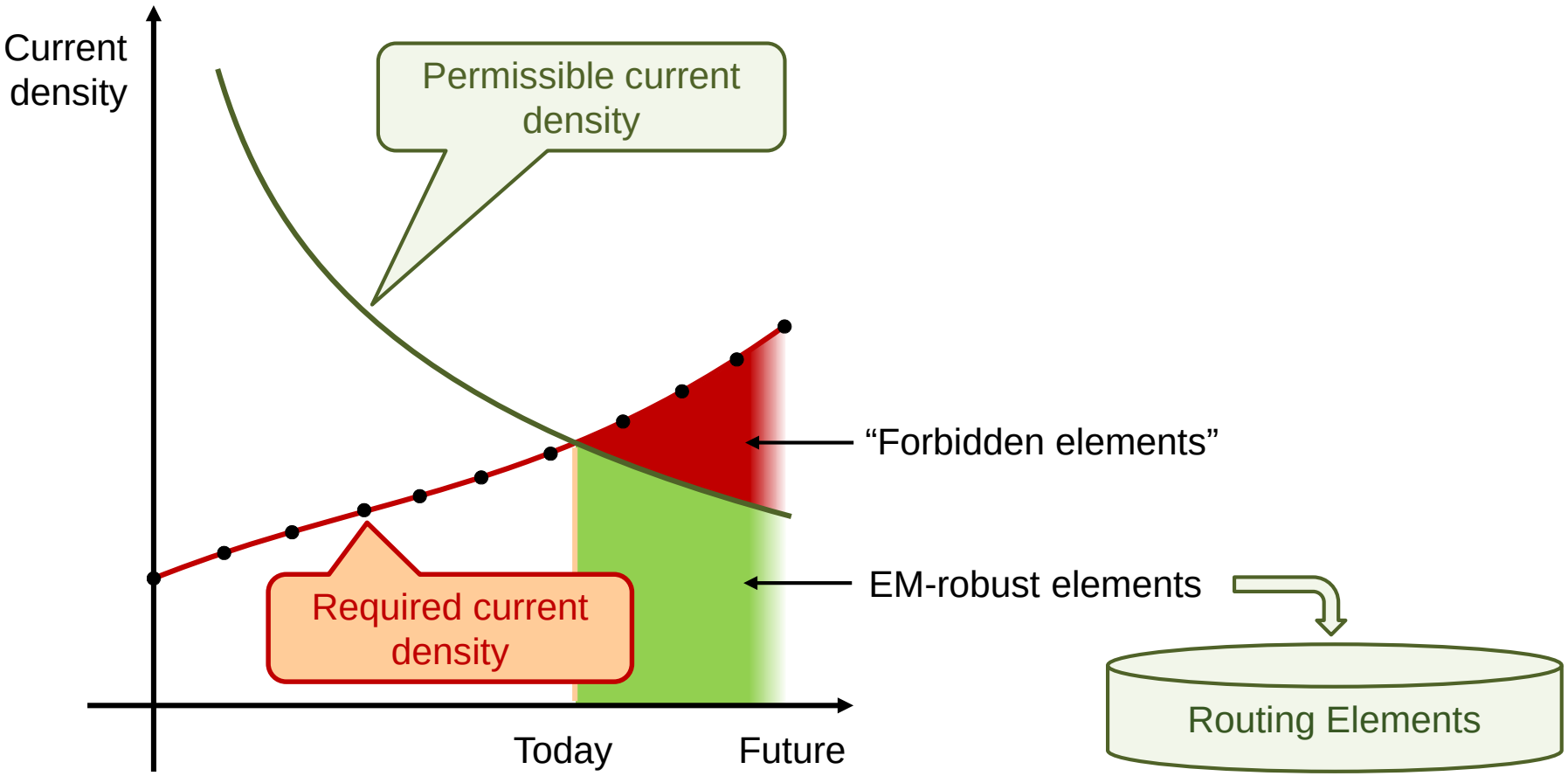




© J. Lienig, M. Thiele, *Fundamentals of Electromigration-Aware Integrated Circuit Design.* Springer, ISBN 978-3-319-73557-3, 2018.
Figures of Chapter 5: Summary and Outlook


Design Technology
Technology Corners
EM Design Rule Derivation
Pattern Generator
EM Verification
Routing Elements
Physical Design
Physical Verification
and Signoff


Current density
Permissible current density
"Forbidden elements"
EM-robust elements
Required current density
Today
Future
Routing Elements